

FCC ID: HBO-HW620

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V05

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$\left[\frac{\text{max. power of channel, including tune-up tolerance, mW}}{\text{min. test separation distance, mm}} \right] * \sqrt{f(\text{GHz})} \leq 3.0$$
 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where $f(\text{GHz})$ is the RF channel transmit frequency in GHz;

Power and distance are rounded to the nearest mW and mm before calculation;

The result is rounded to one decimal place for comparison;

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

We use 5mm as separation distance to calculate.

Maximum measured transmitter power:

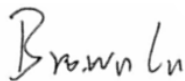
BT DSS:

Transmit Frequency (GHz)	Mode	Measured Power (dBm)	Tune-up power (dBm)	Max tune-up	Result	1-g SAR
				power(dBm)	calculation	
2.402	GFSK	-1.47	-1±1	0	0.3100	3
2.441	GFSK	-1.39	-1±1	0	0.3125	3
2.48	GFSK	-1.87	-1±1	0	0.3150	3
2.402	$\pi/4$ -DQPSK	-2.64	-2±1	-1	0.2462	3
2.441	$\pi/4$ -DQPSK	-2.50	-2±1	-1	0.2482	3
2.48	$\pi/4$ -DQPSK	-2.72	-2±1	-1	0.2502	3
2.402	8DPSK	-2.41	-2±1	-1	0.2462	3
2.441	8DPSK	-2.25	-2±1	-1	0.2482	3
2.48	8DPSK	-2.65	-2±1	-1	0.2502	3
2.402	GFSK	-1.91	-2±1	-1	0.2462	3
2.440	GFSK	-1.95	-2±1	-1	0.2482	3
2.48	GFSK	-1.97	-2±1	-1	0.2502	3

Conclusion:

For the max result : $0.3150 \leq 3.0$ for 1-g SAR extremity SAR, No SAR is required.

Signature:



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